	 	notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/842,531	KIM, HYON T.	
Examiner	Art Unit	
Hai V. Nguyen	2142	

SEARCHED			
Class	Subclass	Date	Examiner
709	227, 228	2/9/2006	HN
710	8,10	2/9/2006	HN
710	11, 12	2/9/2006	HN
<u> </u>			

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
-			

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR	
EAST Search - US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB. (see search history printout)	2/9/2006	ни	